Notice of References Cited Application/Control No. 10/519,854 Examiner Hae M. Hyeon Applicant(s)/Patent Under Reexamination CLAUS ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,842,544	06-1989	Birch et al.	439/387
	В	US-5,522,733 A	06-1996	White et al.	439/395
	С	US-5,810,616 A	09-1998	Ivey, David Ernest	439/395
	D	US-6,641,426 B2	11-2003	Saitoh, Yasushi	, 439/395
	Ε	US-6,670,880 B1	12-2003	Hall et al.	336/132
	F	US-6,676,436 B2	01-2004	Gaidosch, Othmar	439/393
	G	US-6,783,379 B2	08-2004	Kerscher et al.	439/191
	Н	US-2004/0256127 A1	12-2004	Brenner et al.	174/021.00R
	ı	US-6,848,924 B2	02-2005	Frisch, Herbert	439/191
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т			,		

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.